

*A word from the editor . . .*

As I told you last issue, I sent my comments and most of the text for the "International Report" to our Manager of Publication on a floppy diskette. Apparently, the information was immediately usable. What I did was to prepare the material using my word processing program and then write an ASCII file to a 360K floppy disk. For those of you who send me meeting reports, news items, etc., for publication, I'd be glad to receive your material in this manner. I'll still edit the material to some extent, but much of the material will go to the publisher just the way you prepared it.

Helein D. Hitchcock, Editor

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## Regional Correspondents

### *Australia*

Mr. Tony Raftery, Dept. of Physics,  
Queensland Institute of Technology,  
G.P.O. Box 2434,  
Brisbane, Queensland 4001,  
Australia

### *Čzechoslovakia*

Dr. Jaroslav Fiala, Central Research Inst.,  
SKODA,  
31600 Plzen,  
Czechoslovakia

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## ICDD Announces Election of Member-at-Large and Appointments

During the Annual Meeting of the International Centre for Diffraction Data on March 22, 1990, the members in attendance elected James A. Kaduk, Amoco Corporation in Naperville, Illinois, as a Member-at-Large, resolving the tie between Kaduk and Ting C. Huang, IBM Research Division in San Jose, California, which occurred when the ballots were counted in February. The Board of Directors re-elected Gerald G. Johnson, Jr., of the Pennsylvania State University as Treasurer and elected Gregory P. Hamill, GTE Laboratories, Waltham, Massachusetts, as Chairman of the Technical Committee.

## 1990

### **Powder Diffraction Satellite Meeting of 15th IUCr July 16-19, 1990**

#### **Toulouse, France**

The provisional list of topics includes:

1. Accuracy in data collection; high resolution diffraction; standard reference materials.
2. Sample characteristics from powder data, particularly by means of pattern fitting methods.
3. Practical aspects of structure determination from powder data: indexing, structure solution, refinement.
4. Recent applications with emphasis on time- and temperature-resolved studies of materials.
5. Advances in phase identification and quantitative analysis.

For further information: CEMES-LOE CNRS, Powder Diffraction, 29, rue Jeanne Marvig, BP 4347, 31055 Toulouse Cedex, France.

### **International Union of Crystallography 15th General Assembly and International Congress July 19-28, 1990**

#### **Bordeaux, France**

Contact: Prof. M. Hospital, Laboratoire de Cristallographie et de Physique Cristalline, Université de Bordeaux 1, 351 Cours de la Liberation, F 33405 Talence Cedex, France.

### **1990 Annual Denver Conference on Applications of X-Ray Analysis July 30-August 3, 1990**

#### **Steamboat Springs, Colorado, USA.**

The general area of emphasis this year is X-Ray Fluorescence. The Plenary Session topic is Surface and Near Surface X-Ray Spectroscopy. Special Session Topics include: Problems in the Determination of Low Concentration Levels by X-Ray Spectrometry, Long Wave-Length X-Ray Spectrometry, Geological Applications of X-Ray Spectrometry, XRF in Analytical Problem Solving, Non-Ambient Applications of XRD, X-Ray Scattering from Polymers, Solid State and Position-Sensitive Detectors for XRD, and Applications of PC's in Powder Diffraction. Scheduled Tutorial Workshops are: Introduction to Fundamental Parameters Procedures in XRF, Sample Preparation Methods for XRF, Open Session on Problems in XRF, Total Reflection XRF Analysis, Quantitative Phase Analysis for Environmentally Sensitive Materials, Influence of Systematic Experimental Errors on Phase Identification Using the Powder Diffraction File, Profile Fitting in XRD, Indexing Methods for Powder Diffraction Patterns, and Precision Measurement of Lattice Parameters.

Contact: Lynne Bonno, Conference Secretary, Department of Engineering, University of Denver, Denver, CO 80208, USA. Phone (303) 871-3515.

### **14th Conference on Applied Crystallography August 5-8, 1990**

#### **Cieszyn, Poland**

The conference is organized by the Institute of Physics and Chemistry of Metals at the Silesian University in Katowice